

CoolSiC™ 400V CoolSiC™ G2 MOSFET

Features

- Ideal for high frequency switching and synchronous rectification
- Commutation robust fast body diode with low Q_{fr}
- Low R_{DS(on)} dependency on temperature
 Benchmark gate threshold voltage, V_{GS(th)} = 4.5 V
 Recommended gate driving voltage 0 V to 18 V
- .XT interconnection technology for best-in-class thermal performance
- 100% avalanche tested

Potential applications

- SMPS
- Solar PV inverters
- Energy storage, UPS and battery formation
- Class-D audio
- Motor drives

Product validation

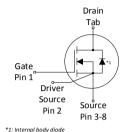
Fully qualified according to JEDEC for Industrial Applications

Table 1 **Kev Performance Parameters**

Parameter	Value	Unit
V_{DS}	400	V
$R_{\mathrm{DS(on),typ}}$	25.4	mΩ
I _D	68	А
$Q_{ m oss}$	59	nC
E _{oss}	4.2	μЈ
Q_{G}	36	nC











Type/Ordering Code	Package	Marking	Related Links
IMT40R025M2H	PG-HSOF-8	40R025M2	-

Public

400V CoolSiC™ G2 MOSFET IMT40R025M2H



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1 Maximum ratings

at T_A =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davameter	Cymphal	Values			11-4	Nata/Task Canditian	
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition	
Continuous drain current ¹⁾	I _D	-	-	68 48 9	A	$V_{\rm GS}$ =18 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =18 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =18 V, $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =40 °C/W ²⁾	
Pulsed drain current ³⁾	I _{D,pulse}	-	-	204	А	T _C =25 °C	
Avalanche energy, single pulse ⁴⁾	E _{AS}	-	-	93	mJ	$I_{\rm D}$ =15.7 A, $R_{\rm GS}$ =25 Ω	
Avalanche energy, repetitive	E_{AR}	-	-	0.47	mJ	$I_{\rm D}$ =15.7 A, $R_{\rm GS}$ =25 Ω	
Gate source voltage (static)	$V_{\rm GS,DC}$	-7	-	23	V	-	
Gate source voltage (transient)	$V_{\rm GS,AC}$	-10	-	25	V	t _{pulse} ≤500 ns, duty cycle ≤ 1%	
Power dissipation	P _{tot}	-	-	214 3.8	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =40 °C/W ²⁾	
Storage temperature	$T_{\rm stg}$	-55	-	150	°C	-	
Operating junction temperature	T _j	-55	-	175	°C	-	

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature at 25°C. For higher case temperature please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information.

⁴⁾ See Diagram 19 for more detailed information.



2 Thermal characteristics

Table 3 Thermal characteristics

Davamatav	Symbol	Values			l lmit	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition	
Thermal resistance, junction - case	R_{thJC}	-	-	0.7	°C/W	-	
Thermal resistance, junction -							
ambient,	R_{thJA}	-	-	40	°C/W	-	
6 cm ² cooling area ⁵⁾							

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

3 Operating range

Table 4 Operating range

Parameter	Symbol	Values			Unit	Note/ Test Condition	
raiailietei	Symbol		Тур.	Max.	Onit	Note/ rest condition	
Recommended turn-on voltage	$V_{GS(on)}$	-	18	-	V	-	
Recommended turn-off voltage	$V_{GS(off)}$	-	0	-	V	-	

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4 Electrical characteristics

at T_i =25 °C, unless otherwise specified

Table 5 Static characteristics

Parameter	Symbol	Values			Limit	Nata/Task Canditian
raiailletei	Syllibol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Drain-source breakdown voltage	$V_{(BR)DSS}$	400	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =0.56 mA
Gate threshold voltage ⁶⁾	$V_{\rm GS(th)}$	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 5.6 \rm mA$
Zero gate voltage drain current	I _{DSS}	-	1 2	75 -	μΑ	$V_{\rm DS}$ =400 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =400 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =175 °C
Gate-source leakage current	I_{GSS}	-	1	100	nA	V _{GS} =20 V, V _{DS} =0 V
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	25.4 36.5 31.1		mΩ	$V_{\rm GS}$ =18 V, $I_{\rm D}$ =15.7 A, $T_{\rm j}$ =25 °C $V_{\rm GS}$ =18 V, $I_{\rm D}$ =15.7 A, $T_{\rm j}$ =175 °C $V_{\rm GS}$ =15 V, $I_{\rm D}$ =15.7 A, $T_{\rm j}$ =25 °C
Gate resistance	$R_{\rm G}$	-	3.3	5.0	Ω	-

⁶⁾ Tested after 1ms pulse at V_{GS} = +20V.

Table 6 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition	
raiametei	Min. Typ. Max.		Offic	Note, rest condition			
Input capacitance	C _{iss}	-	1200	1690	pF	V _{GS} =0 V, V _{DS} =200 V, <i>f</i> =1 MHz	
Output capacitance	$C_{\rm oss}$	-	180	-	pF	V _{GS} =0 V, V _{DS} =200 V, <i>f</i> =1 MHz	
Reverse transfer capacitance	C _{rss}	-	14	-	pF	V _{GS} =0 V, V _{DS} =200 V, f=1 MHz	
Effective output capacitance, energy related ⁷⁾	$C_{ m o(er)}$	-	211	-	pF	V _{GS} =0 V, V _{DS} =0200 V	
Effective output capacitance, time related ⁸⁾	$C_{ m o(tr)}$	-	290	-	pF	$I_{\rm D}$ =constant, $V_{\rm GS}$ =0 V, $V_{\rm DS}$ =0200 V	
Turn-on delay time ⁹⁾	$t_{ m d(on)}$	-	12.5	-	ns	$V_{\rm DD}$ =200 V, $V_{\rm GS}$ =018 V, $I_{\rm D}$ =15.7 A, $R_{\rm G,ext}$ =1.8 Ω	
Rise time ⁹⁾	t _r	-	11.9	-	ns	$V_{\rm DD}$ =200 V, $V_{\rm GS}$ =018 V, $I_{\rm D}$ =15.7 A, $R_{\rm G,ext}$ =1.8 Ω	
Turn-off delay time ⁹⁾	$t_{ m d(off)}$	-	19.9	-	ns	$V_{\rm DD}$ =200 V, $V_{\rm GS}$ =180 V, $I_{\rm D}$ =15.7 A, $R_{\rm G,ext}$ =1.8 Ω	
Fall time ⁹⁾	t _f	-	7.9	-	ns	$V_{\rm DD}$ =200 V, $V_{\rm GS}$ =180 V, $I_{\rm D}$ =15.7 A, $R_{\rm G,ext}$ =1.8 Ω	

⁷⁾ $C_{\rm o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 200 V.

⁸⁾ $C_{\text{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 200 V.

⁹⁾ Refer to Table 9 for test setup.

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Table 7 Gate Charge Characteristics 10)

Darameter	Symbol	Values			Linit	Note / Test Condition
Parameter	Syllibol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	9.8	-	nC	$V_{\rm DD}$ =200 V, $I_{\rm D}$ =15.7 A, $V_{\rm GS}$ =0 to 18 V
Gate to drain charge	$Q_{ m gd}$	-	7.5	-	nC	$V_{\rm DD}$ =200 V, $I_{\rm D}$ =15.7 A, $V_{\rm GS}$ =0 to 18 V
Gate charge total	$Q_{ m g}$	-	36	-	nC	$V_{\rm DD}$ =200 V, $I_{\rm D}$ =15.7 A, $V_{\rm GS}$ =0 to 18 V
Gate charge total, sync. FET	$Q_{\rm g(sync)}$	-	34	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 18 V
Output charge	$Q_{\rm oss}$	-	59	-	nC	V _{DS} =200 V, V _{GS} =0 V
Output Energy	E _{oss}	-	4.2	-	μJ	V _{DS} =200 V, V _{GS} =0 V

 $^{^{10)}}$ $\,$ As per JEP192, Guidelines for Gate Charge ($Q_{\rm G}$) Test Method for SiC MOSFET.

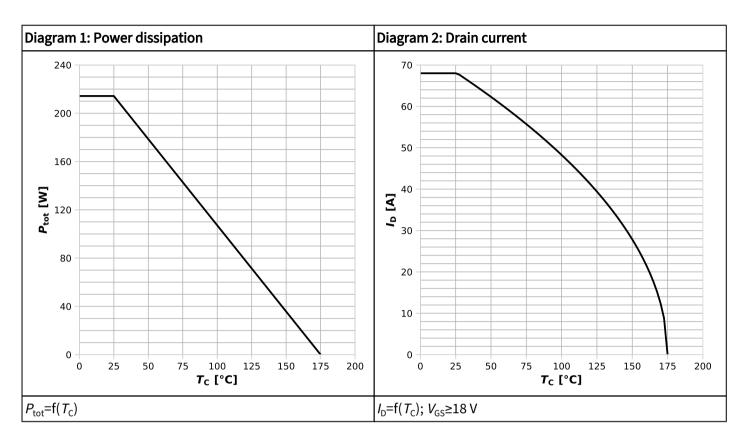
Table 8 Reverse diode characteristics

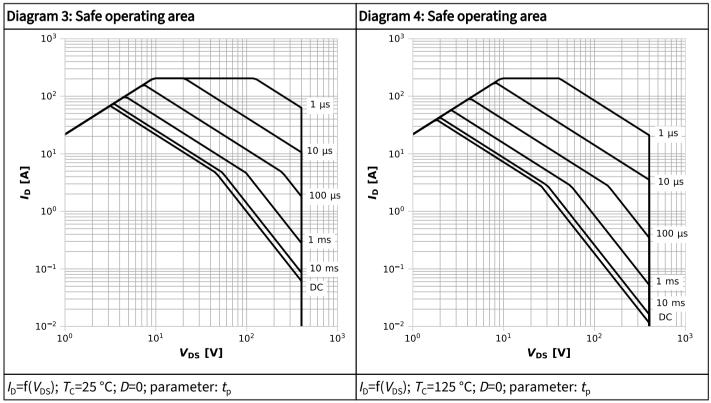
Darameter	Symbol	Values			Unit	Note/Test Condition	
Parameter	Symbol	Min.	Тур.	Мах.	Offic	Note/ Test Condition	
Diode continuous forward current	I_{S}	-	-	32	А	<i>T</i> _c =25 °C	
Diode pulse current	I _{S,pulse}	-	-	204	А	<i>T</i> _C =25 °C, <i>t</i> _{pulse} ≤250 ns	
Diode forward voltage	$V_{\rm SD}$	-	3.5	4.3	V	$V_{\rm GS}$ =0 V, $I_{\rm S}$ =15.7 A, $T_{\rm j}$ =25 °C	
MOSFET forward recovery time	t _{fr}	-	13.6 8.9	-	ns	V_R =200 V, I_S =15.7 A, di_S/dt =1000 A/ μ s V_R =200 V, I_S =15.7 A, di_S/dt =4000 A/ μ s	
MOSFET forward recovery charge ¹¹⁾	Q_{fr}	-	55 116	-	nC	$V_{\rm R}$ =200 V, $I_{\rm S}$ =15.7 A, d $i_{\rm S}$ /d t =1000 A/ μ s $V_{\rm R}$ =200 V, $I_{\rm S}$ =15.7 A, d $i_{\rm S}$ /d t =4000 A/ μ s	

 $^{^{11)}~~}Q_{\rm fr}$ includes $Q_{\rm oss}.$ Refer to Table 10 for test setup.

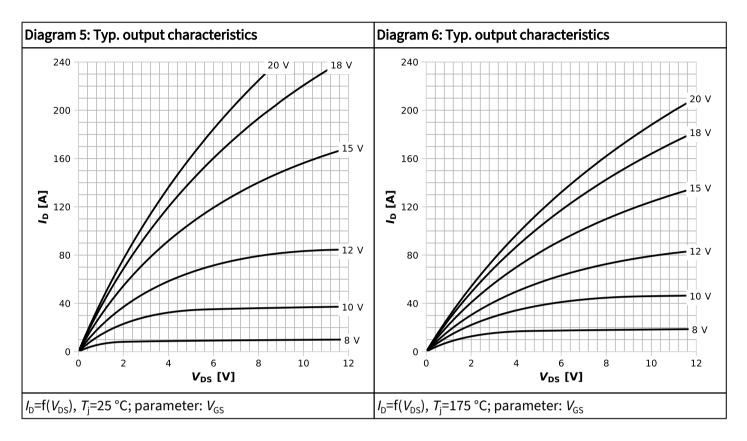


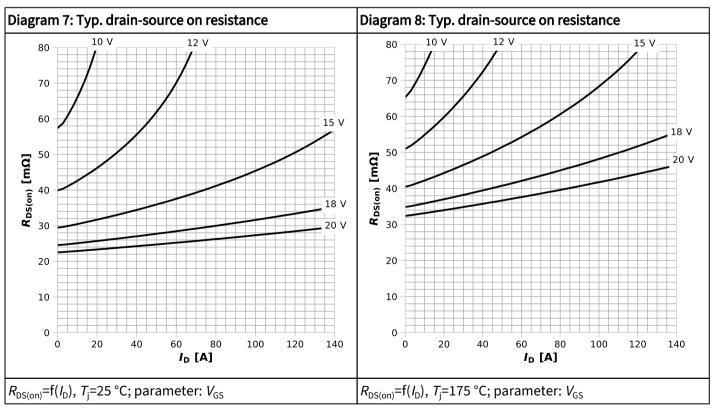
5 Electrical characteristics diagrams



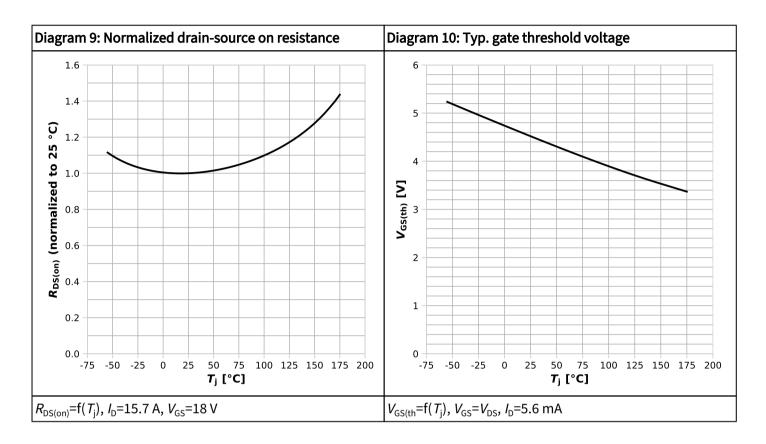


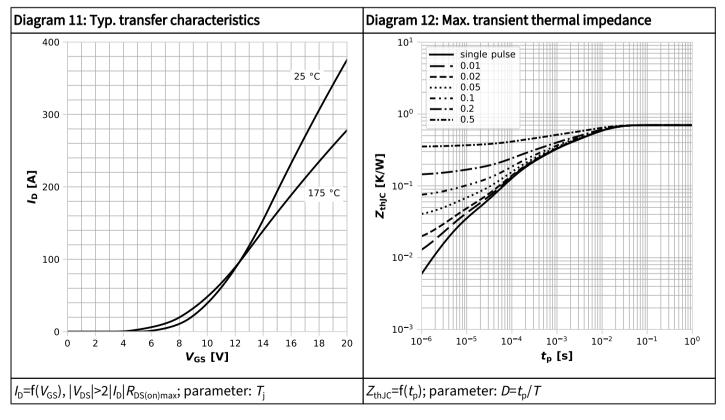




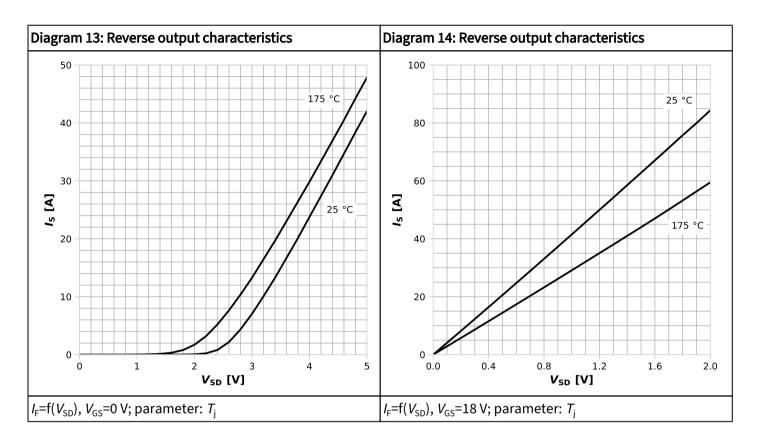


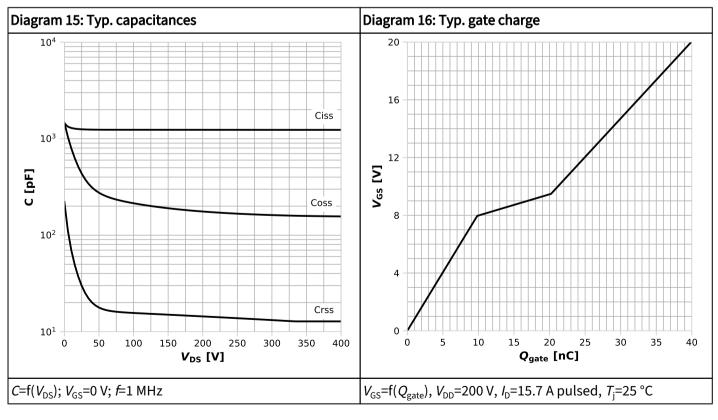




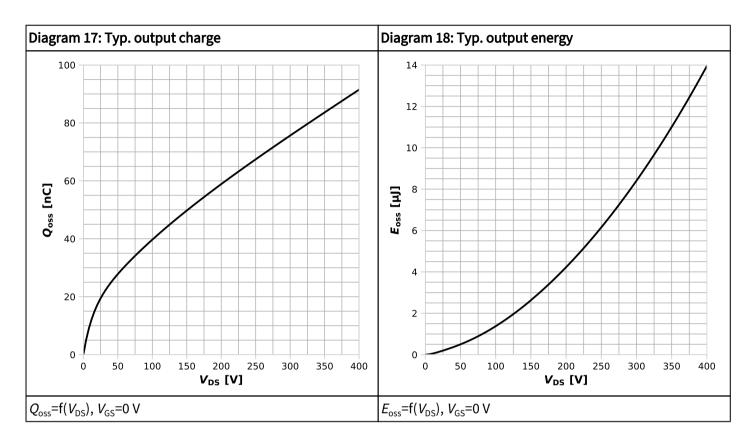


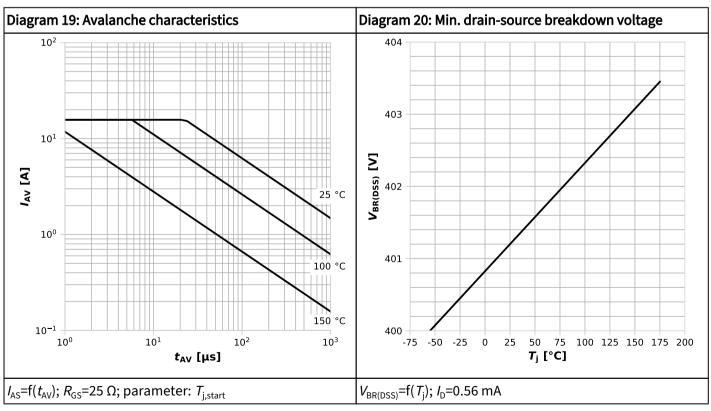




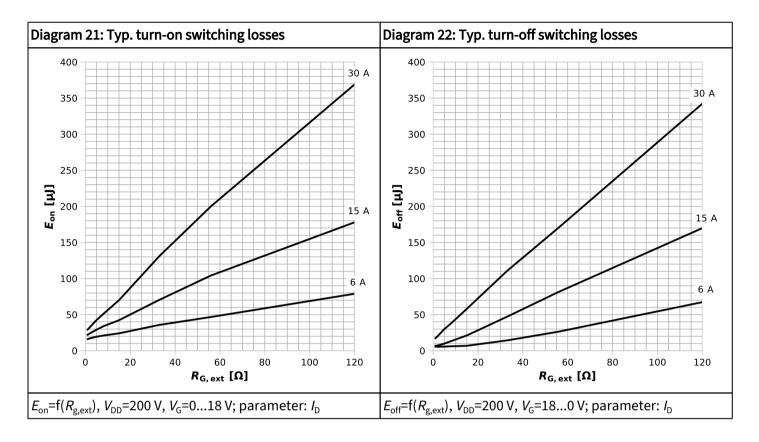


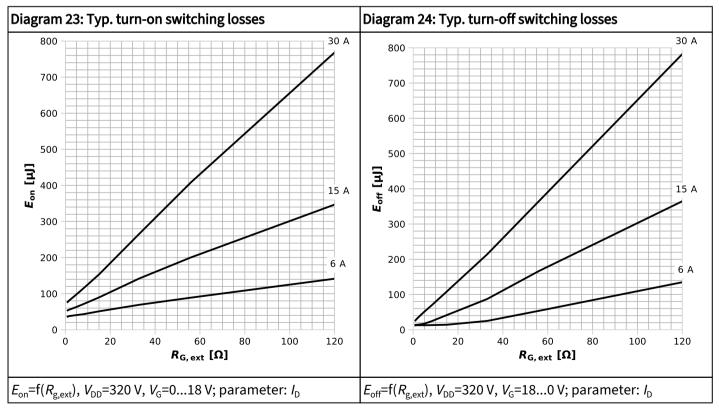














6 Test Circuits

Table 9 Switching times (CoolSiC)

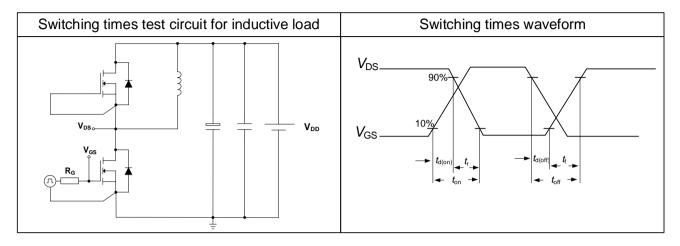
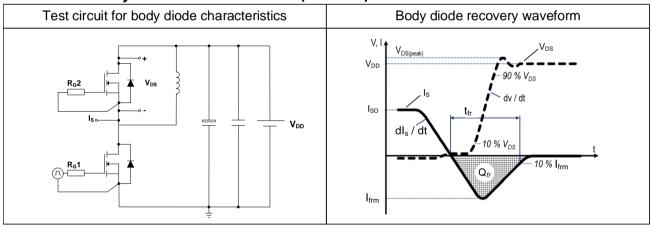
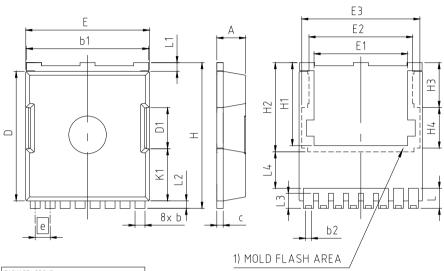


Table 10 Body diode characteristics (CoolSiC)





7 Package Outlines



PACKAGE - GROUP NUMBER:	PG-HSOF-8-U02						
DIMENSIONS	MILLIM	ETERS					
DIMENSIONS	MIN.	MAX.					
Α	2.20	2.40					
b	0.70	0.90					
b1	9.70	9.90					
b2	0.42	0.50					
С	0.40	0.60					
D	10.28	10.58					
D1	3.30						
E	9.70	10.10					
E1	7.50						
E2	8.50						
E3	9.46						
е	1.20 (BSC)						
н	11.48	11.88					
H1	6.55	6.95					
H2	7.	15					
Н3	3.	59					
H4	3.:	26					
N	8	3					
K1	4.18						
L	1.40	1.80					
L1	0.50	0.90					
L2	0.50	0.70					
L3	1.00	1.30					
L4	2.62	2.81					

1) PARTIALLY COVERED WITH MOLD FLASH

Figure 1 Outline PG-HSOF-8, dimensions in mm

Public

400V CoolSiC™ G2 MOSFET IMT40R025M2H



Revision History

IMT40R025M2H

Revision 2024-04-27, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.0	2024-04-26	Release of preliminary version
2.0	2024-04-27	Release of final

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